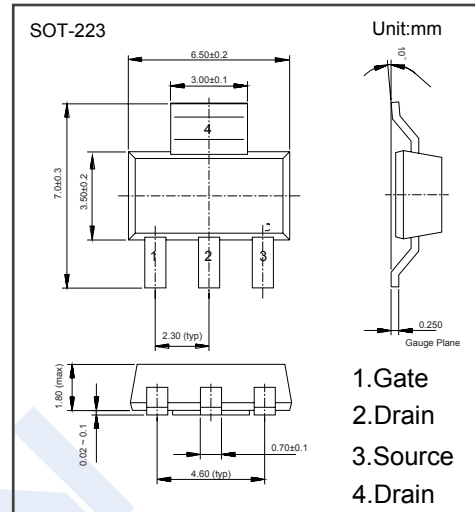
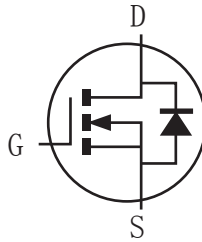


N-Channel MOSFET

ZXMN10A08G (KXMN10A08G)

■ Features

- $V_{DS} (V) = 100V$
- $I_D = 2.9 A (V_{GS} = 10V)$
- $R_{DS(ON)} < 250m\Omega (V_{GS} = 10V)$
- $R_{DS(ON)} < 300m\Omega (V_{GS} = 6V)$



■ Absolute Maximum Ratings $T_a = 25^\circ C$

Parameter	Symbol	Rating	Unit	
Drain-Source Voltage	V_{DS}	100	V	
Gate-Source Voltage	V_{GS}	± 20		
Continuous Drain Current @ $V_{GS} = 10V$	I_D	$T_A = 25^\circ C$ (Note.1)	2.9	A
		$T_A = 70^\circ C$ (Note.1)	2.3	
		$T_A = 25^\circ C$ (Note.2)	2	
Pulsed Drain Current	I_{DM}	11		
Power Dissipation	P_D	$T_A = 25^\circ C$ (Note.2)	2	W
		$T_A = 25^\circ C$ (Note.1)	3.9	mW/ $^\circ C$
Linear derating factor		16	W	
Linear derating factor		31	mW/ $^\circ C$	
Thermal Resistance.Junction- to-Ambient	R_{thJA}	(Note.2)	62.5	$^\circ C/W$
		(Note.1)	32	
Junction Temperature	T_J	150	$^\circ C$	
Storage Temperature Range	T_{stg}	-55 to 150		

Note.1: For a device surface mounted on FR4 PCB measured at $t \leq 10$ sec.

Note.2: For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz in still air conditions.

N-Channel MOSFET

ZXMN10A08G (KXMN10A08G)

■ Electrical Characteristics $T_a = 25^\circ\text{C}$

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V_{DS}	$I_D=250\ \mu\text{A}$, $V_{GS}=0\text{V}$	100			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=100\text{V}$, $V_{GS}=0\text{V}$			0.5	μA
Gate-Body Leakage Current	I_{GSS}	$V_{DS}=0\text{V}$, $V_{GS}=\pm 20\text{V}$			± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_D=250\ \mu\text{A}$	2		4	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=10\text{V}$, $I_D=3.2\text{A}$ (Note.1)			250	m Ω
		$V_{GS}=6\text{V}$, $I_D=2.6\text{A}$ (Note.1)			300	
Forward Transconductance	g_{FS}	$V_{DS}=15\text{V}$, $I_D=3.2\text{A}$ (Note.1)		5		S
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}$, $V_{DS}=50\text{V}$, $f=1\text{MHz}$		405		pF
Output Capacitance	C_{oss}			28.2		
Reverse Transfer Capacitance	C_{rss}			14.2		
Total Gate Charge	Q_g	$V_{GS}=5\text{V}$, $V_{DS}=50\text{V}$, $I_D=1.2\text{A}$		4.2		nC
				7.7		
Gate Source Charge	Q_{gs}	$V_{GS}=10\text{V}$, $V_{DS}=50\text{V}$, $I_D=1.2\text{A}$		1.8		nC
Gate Drain Charge	Q_{gd}			2.1		
Turn-On DelayTime	$t_{d(on)}$	$V_{GS}=10\text{V}$, $V_{DS}=30\text{V}$, $I_D=1.2\text{A}$, $R_G=6\ \Omega$		3.4		ns
Turn-On Rise Time	t_r			2.2		
Turn-Off DelayTime	$t_{d(off)}$			8		
Turn-Off Fall Time	t_f			3.2		
Body Diode Reverse Recovery Time	t_{rr}		$I_F=1.2\text{A}$, $di/dt=100\text{A}/\mu\text{s}$, $T_j=25^\circ\text{C}$		27	
Body Diode Reverse Recovery Charge	Q_{rr}			32		nC
Maximum Body-Diode Continuous Current	I_S				5	A
Pulsed source current	I_{SM}				11	
Diode Forward Voltage	V_{SD}	$I_S=3.2\text{A}$, $V_{GS}=0\text{V}$, $T_j=25^\circ\text{C}$			0.95	V

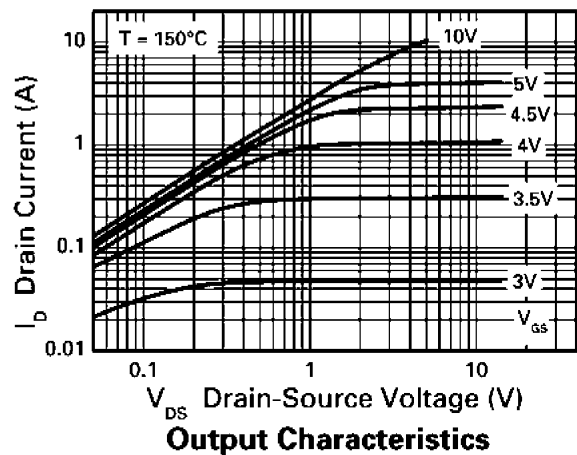
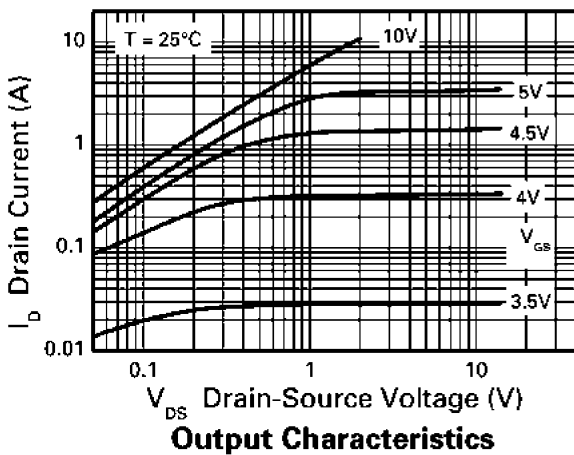
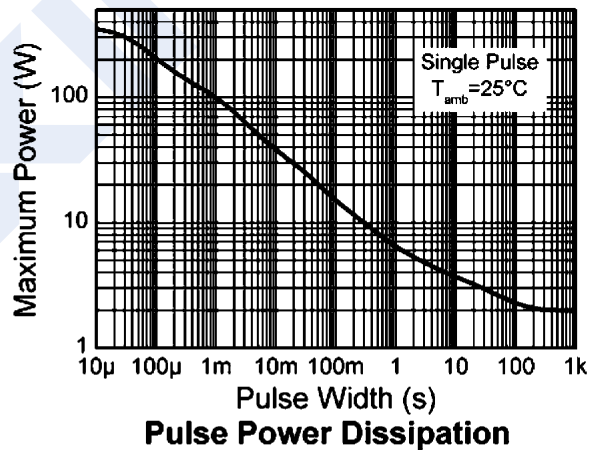
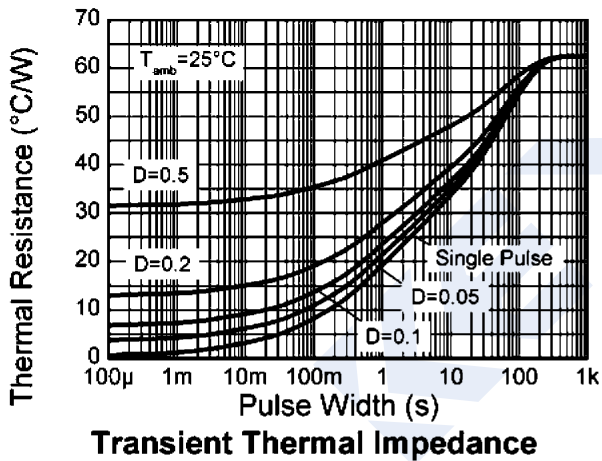
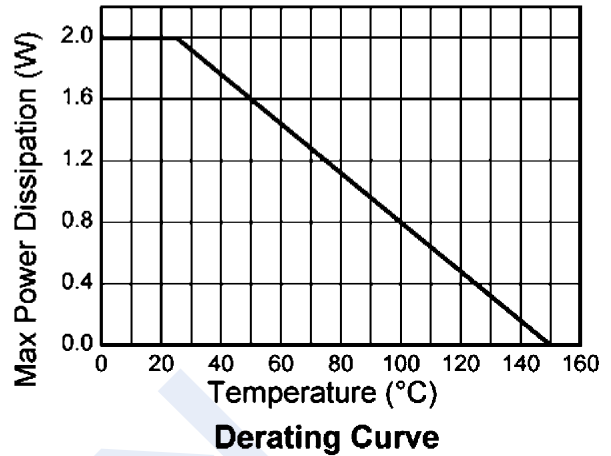
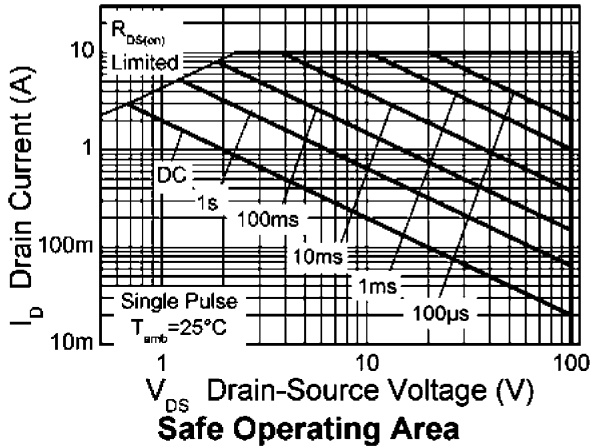
Note.1: Measured under pulsed conditions. Pulse width $\leq 300\ \mu\text{s}$; duty cycle $\leq 2\%$.

■ Marking

Marking	ZXMN
	10A08

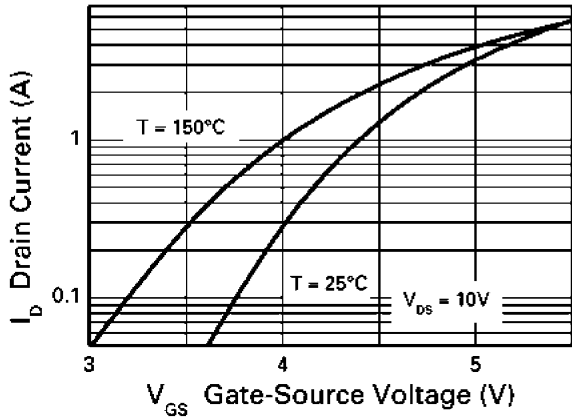
N-Channel MOSFET ZXMN10A08G (KXMN10A08G)

■ Typical Characteristics

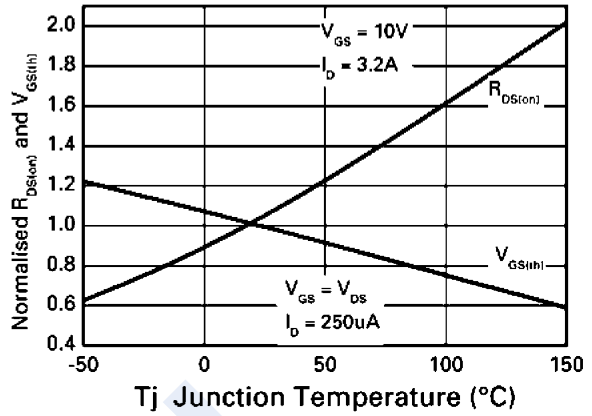


N-Channel MOSFET ZXMN10A08G (KXMN10A08G)

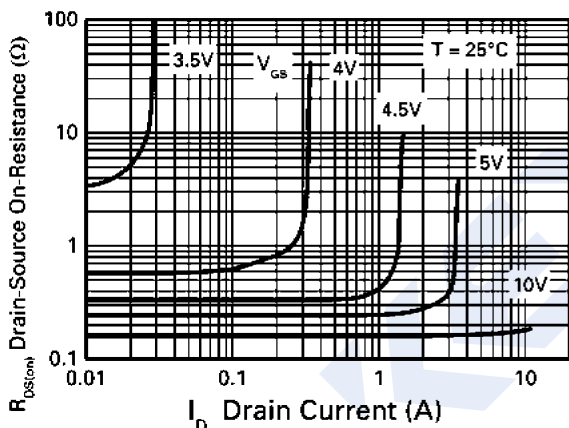
■ Typical Characteristics



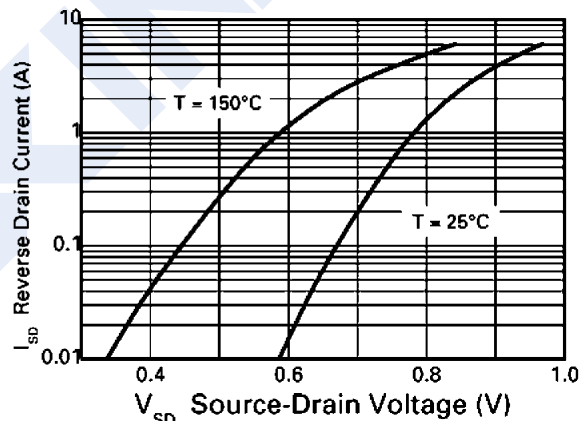
Typical Transfer Characteristics



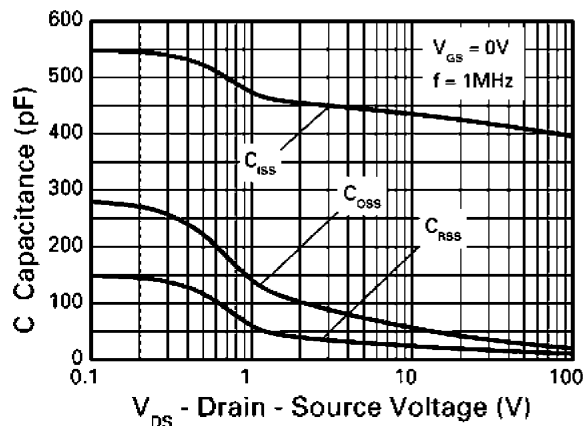
Normalised Curves v Temperature



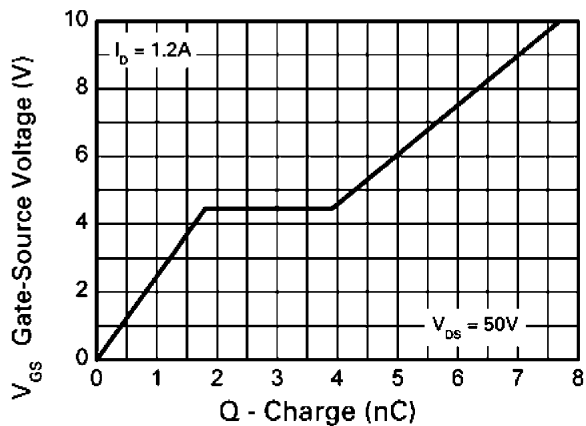
On-Resistance v Drain Current



Source-Drain Diode Forward Voltage



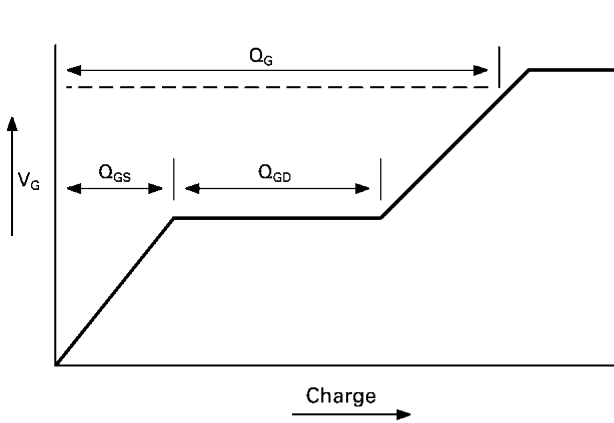
Capacitance v Drain-Source Voltage



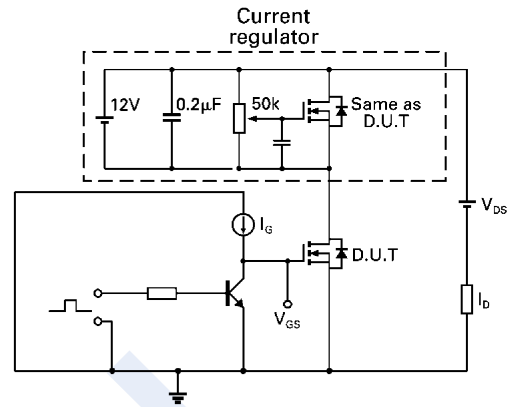
Gate-Source Voltage v Gate Charge

N-Channel MOSFET ZXMN10A08G (KXMN10A08G)

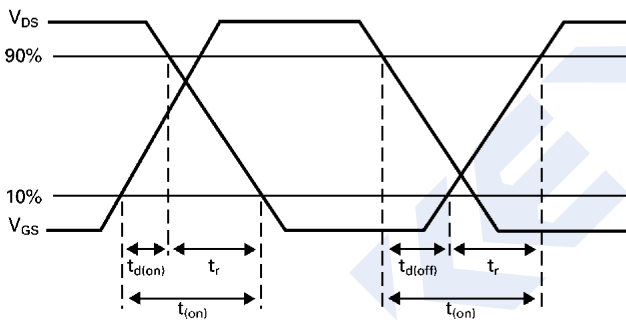
■ Typical Characteristics



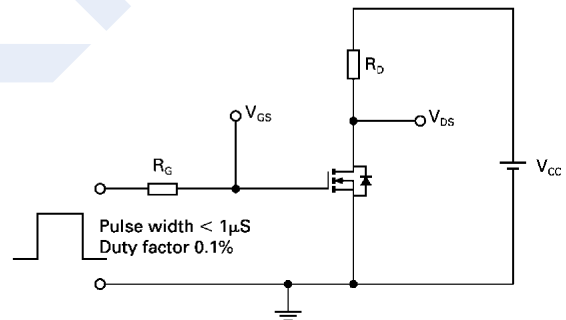
Basic gate charge waveform



Gate charge test circuit



Switching time waveforms



Switching time test circuit